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(54) **METHOD AND SYSTEM FOR MEASURING CAPACITANCE DIFFERENCE BETWEEN CAPACITIVE ELEMENTS**

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See application file for complete search history.

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(57) **ABSTRACT**
Methods and systems for measuring capacitance difference are disclosed. In one aspect, first and second capacitive elements are connected between voltage receiving nodes for receiving first and second DC voltages and nodes connectable to a third DC voltage via a first, resp. second switch. Further, in a first phase, a voltage difference is applied to charge the capacitive elements and the switches are alternately closed. First resulting currents are measured. Further, in a second phase, the first and second DC voltages are applied alternately and the switches are alternately closed. Second resulting currents are measured. The capacitance difference can be determined from the first and second resulting currents.

21 Claims, 9 Drawing Sheets

